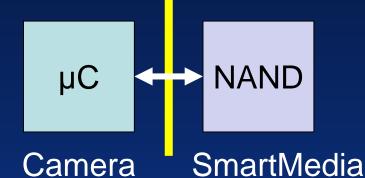


How Good Is Your Memory? An Architect's Look Inside SSDs

Michael Abraham (mabraham@micron.com) Business Line Manager Micron Technology, Inc.



Farly Storage Optimizations



Slow

Early obsolescence

Inexpensive solution

μC/

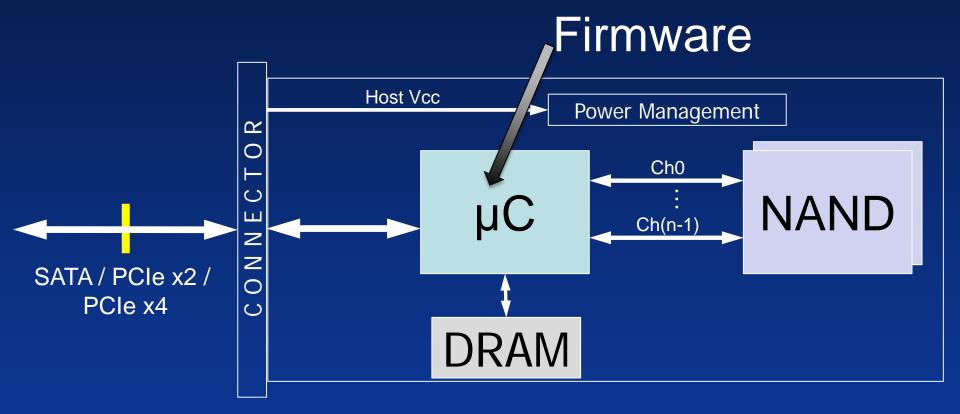
SRAM

CF/USB/SD

FasterUpgradeableSlightly more expensive

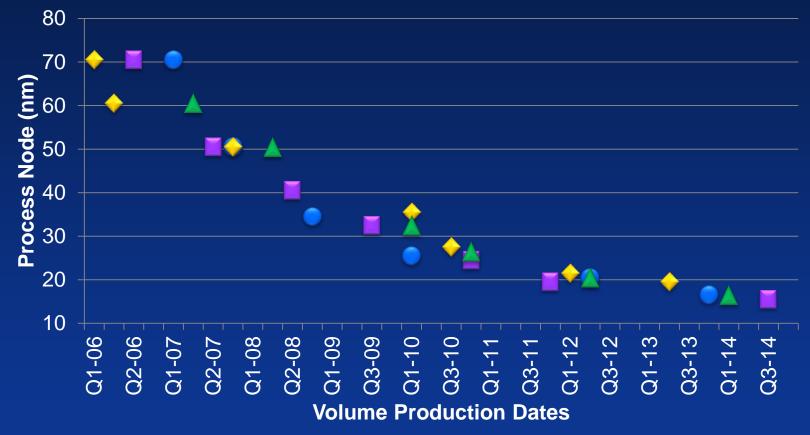
Santa Clara, CA August 2015 NAND











• The industry went through 7-9 NAND lithography transitions

Santa Clara, CA August 2015

Data based on publicly known information.



ry What Happened in That Decade?

- Density: 2Gb \rightarrow 128Gb per die
- Interface: 40MHz SDR \rightarrow 266MHz DDR
- Bits per Cell: SLC \rightarrow MLC \rightarrow TLC
- Planes: $1 \rightarrow 2 \rightarrow 4$
- Page size: $2KB \rightarrow 16KB$
- Block size: $128KB \rightarrow 8+MB$
- Packaging: 1ch TSOP-48 \rightarrow 4ch BGA
- ECC: 1-bit Hamming \rightarrow RS?/BCH \rightarrow LDPC
- Electrons per Cell State: > $300 \rightarrow 16$
- Engineering skill: 1 college kid \rightarrow 3+ PhDs





Could We Scale Planar NAND Beyond 16nm?

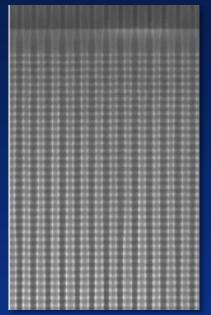
- Lower cost per bit
- Higher ECC
- Longer array operations
- Less data retention
- Less endurance
- More PhDs

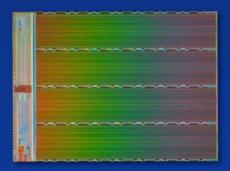




3D NAND: Standing NAND on Its Head

- 3D NAND cell architecture enables significant performance improvement
- 3D NAND cost improvement over planar expands with subsequent nodes

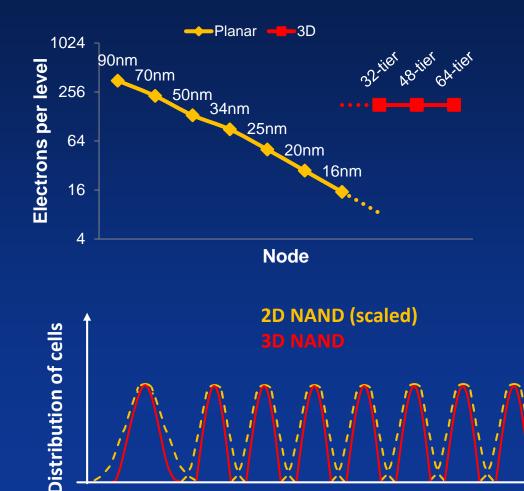








3D NAND Reliability Relative to Planar NAND



3D NAND cell design simultaneously improves performance and reliability

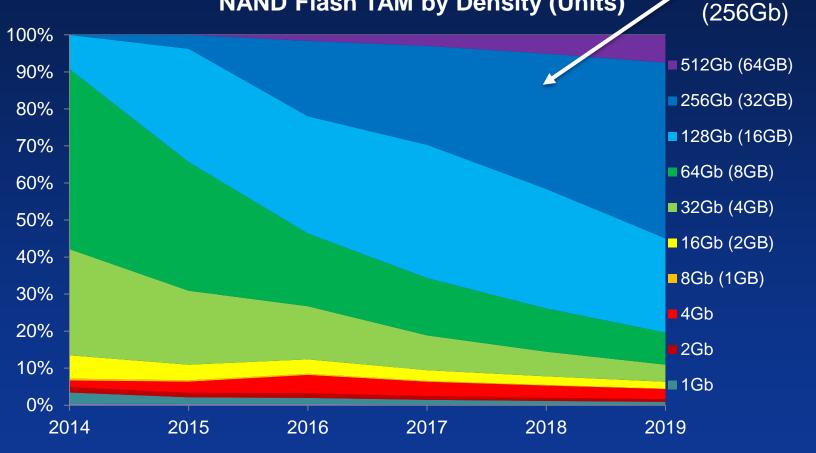
- Vertical stacking allows large number of electrons per cell independent of scaling
- No longer relying on lithography to continue scaling
- Decreased interference between cells translates into higher cycling endurance
- Uses familiar memory materials – CT or FG

Vt



3D NAND Enables New Die Densities

NAND Flash TAM by Density (Units)

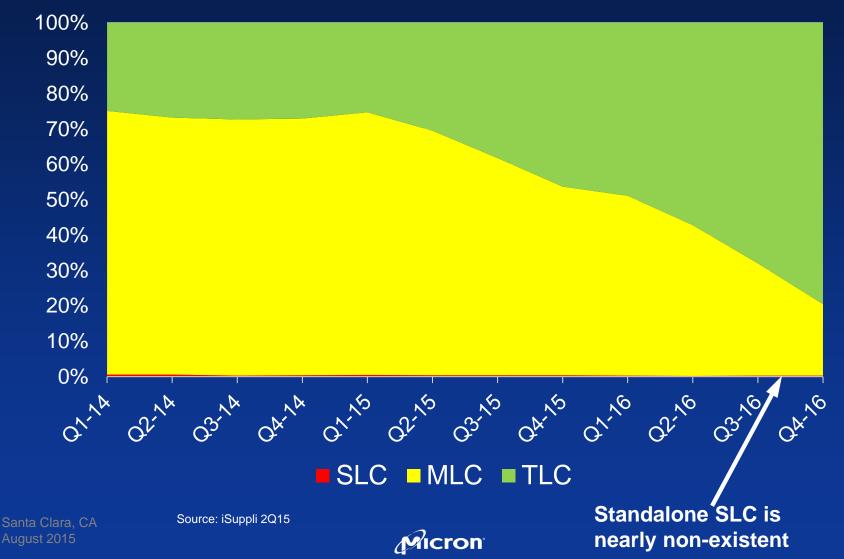




3D NAND in

earnest here

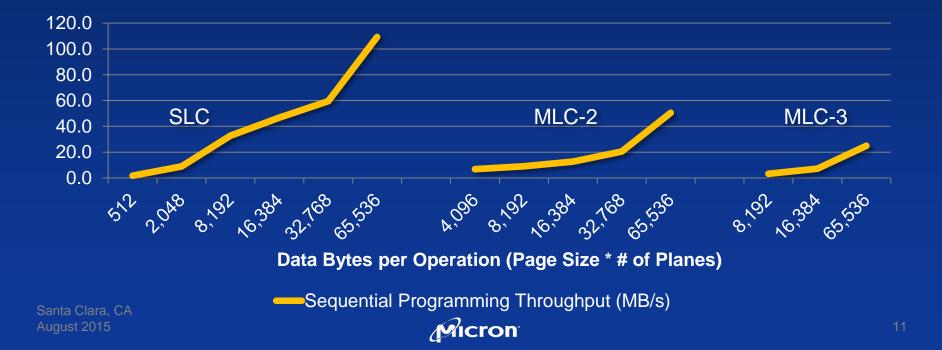






3D NAND Improves Array Performance

 Faster write bandwidth a result of larger number of data bytes per operation and a reduction in tPROG



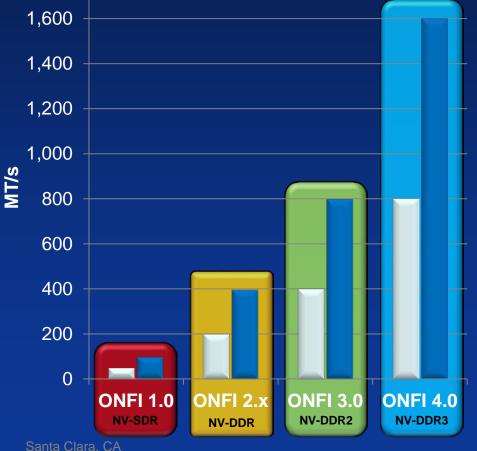


August 2015

ONFI 4 Results in Lower Energy

Micron

Single Channel Package Dual Channel Package



- ONFI 4.0 to be introduced with 3D NAND
- Interface up to 800MT/s throughput
- Reduces energy per bit with 1.2V interface

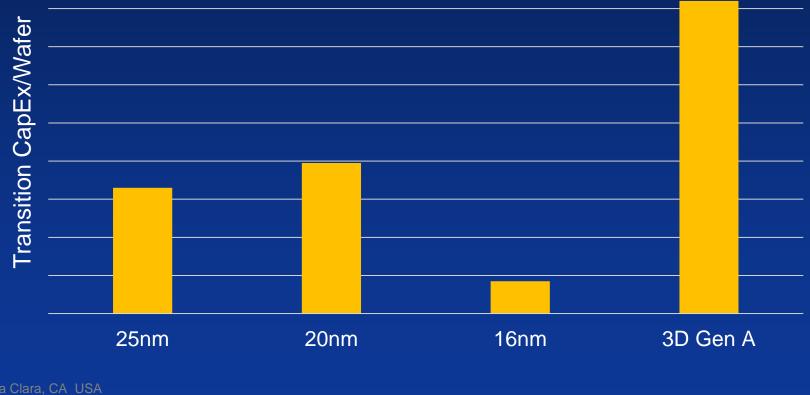


- Density: Introduction of 256Gb
- Interface: ONFI 4.0, 1.2V
- Bits per Cell: MLC, TLC with SLC modes
- Electrons per Cell State: ~200
- Page/block/plane architecture follow traditional NAND scaling path
- Engineering skill: 1 college kid 3+ PhDs





NAND Cost of Transition requires considerably new tooling







Questions?





- Business Line Manager in the Storage Business Unit at Micron
- Former NAND Architect
- Covers emerging memories and 3D XPoint[™]



- IEEE Senior Member
- BS degree in Computer Engineering from Brigham Young University

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Santa Clara, CA August 2015

